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- EPIC™ (Enhanced-Performance Implanted CMOS) Process
- Operating Range 2-V to 5.5-V V<sub>CC</sub>
- Latch-Up Performance Exceeds 250 mA Per JESD 17
- ESD Protection Exceeds JESD 22
  - 2000-V Human-Body Model (A114-A)
  - 200-V Machine Model (A115-A)
  - 1000-V Charged-Device Model (C101)
- Package Options Include Plastic Small-Outline (D), Shrink Small-Outline (DB), Thin Very Small-Outline (DGV), Thin Shrink Small-Outline (PW), and Ceramic Flat (W) Packages, Ceramic Chip Carriers (FK), and Standard Plastic (N) and Ceramic (J) DIPs

#### description

The 'AHC05 devices contain six independent inverters. These devices perform the Boolean function  $Y = \overline{A}$ .

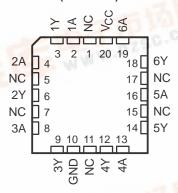
The open-drain outputs require pullup resistors to perform correctly. They can be connected to other open-drain outputs to implement active-low wired-OR or active-high wired-AND functions.

The SN54AHC05 is characterized for operation over the full military temperature range of –55°C to 125°C. The SN74AHC05 is characterized for operation from –40°C to 85°C.

SN54AHC05 . . . J OR W PACKAGE SN74AHC05 . . . D, DB, DGV, N, OR PW PACKAGE (TOP VIEW)



SN54AHC05 . . . FK PACKAGE (TOP VIEW)



NC – No internal connection

# FUNCTION TABLE (each inverter)

	,
INPUT	OUTPUT
Α	Y
Н	L
L	н

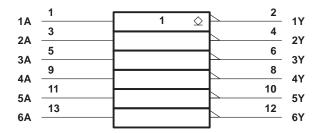
Please be aware that an important notice concerning availability, standard warranty, and use in critical applications of Texas Instruments semiconductor products and disclaimers thereto appears at the end of this data sheet.



# SN54AHC05, SN74AHC05 HEX INVERTERS WITH OPEN-DRAIN OUTPUTS

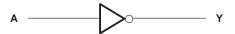
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## logic symbol†



<sup>†</sup> This symbol is in accordance with ANSI/IEEE Std 91-1984 and IEC Publication 617-12. Pin numbers shown are for the D, DB, DGV, J, N, PW, and W packages.

## logic diagram, each inverter (positive logic)



# absolute maximum ratings over operating free-air temperature range (unless otherwise noted)‡

Supply voltage range, V <sub>CC</sub>		0.5 V to 7 V
Input voltage range, V <sub>I</sub> (see Note 1)		0.5 V to 7 V
Output voltage range, VO (see Note 1)		$0.5 \text{ V to V}_{CC} + 0.5 \text{ V}$
Input clamp current, $I_{IK}$ ( $V_I < 0$ )		
Output clamp current, $I_{OK}$ ( $V_O < 0$ or $V_O > V_{CO}$	c)	±20 mA
Continuous output current, $I_O(V_O = 0 \text{ to } V_{CC})$		±25 mA
Continuous current through V <sub>CC</sub> or GND		±50 mA
Package thermal impedance, θ <sub>JA</sub> (see Note 2)		
, <b>3</b> ,11	DB package	
	DGV package	127°C/W
	N package	80°C/W
	PW package	113°C/W
Storage temperature range, T <sub>stg</sub>		–65°C to 150°C

<sup>‡</sup> Stresses beyond those listed under "absolute maximum ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under "recommended operating conditions" is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

- NOTES: 1. The input and output voltage ratings may be exceeded if the input and output current ratings are observed.
  - 2. The package thermal impedance is calculated in accordance with JESD 51.



#### recommended operating conditions (see Note 3)

			SN54A	HC05	SN74A	UNIT	
			MIN	MAX	MIN	MAX	UNIT
Vcc	Supply voltage		2	5.5	2	5.5	V
		V <sub>CC</sub> = 2 V	1.5		1.5		
٧ıH	High-level input voltage	VCC = 3 V	2.1		2.1		V
	V <sub>CC</sub> = 5.5 V	3.85		3.85			
		V <sub>CC</sub> = 2 V		0.5		0.5	
V <sub>IL</sub> Lov	Low-level input voltage	VCC = 3 V		0.9		0.9	V
		V <sub>CC</sub> = 5.5 V	ć	1.65		1.65	
٧ <sub>I</sub>	Input voltage		0	5.5	0	5.5	V
Vo	Output voltage		0	VCC	0	VCC	V
		V <sub>CC</sub> = 2 V	% 0	50		50	μΑ
loL	Low-level output current	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$	4	4		4	mA
		$V_{CC} = 5 V \pm 0.5 V$		8		8	IIIA
Δt/Δν	Input transition rise or fall rate	$V_{CC} = 3.3 \text{ V} \pm 0.3 \text{ V}$		100		100	ns/V
	Input transition rise or fall rate $V_{CC} = 5 \text{ V} \pm$			20		20	115/ V
TA	Operating free-air temperature		-55	125	-40	85	°C

NOTE 3: All unused inputs of the device must be held at V<sub>CC</sub> or GND to ensure proper device operation. Refer to the TI application report, Implications of Slow or Floating CMOS Inputs, literature number SCBA004.

# electrical characteristics over recommended operating free-air temperature range (unless otherwise noted)

PARAMETER	TEST CONDITIONS	vcc	T <sub>A</sub> = 25°C			SN54AHC05		SN74AHC0	UNIT
PARAMETER	TEST CONDITIONS		MIN	TYP	MAX	MIN MA	٩X	MIN MA	K ONII
		2 V			0.1	(	).1	0.	1
V <sub>OL</sub>	I <sub>OL</sub> = 50 μA	3 V			0.1	Q	).1	0	1
		4.5 V			0.1	T.	0.1	0	1 V
	I <sub>OL</sub> = 4 mA	3 V			0.36	Q	).5	0.4	4
	I <sub>OL</sub> = 8 mA	4.5 V			0.36	(2)	).5	0.4	4
lį	V <sub>I</sub> = V <sub>CC</sub> or GND	0 V to 5.5 V			±0.1	+ 2 2	:1*	<u>+</u>	1 μΑ
ICC	$V_I = V_{CC}$ or GND, $I_O = 0$	5.5 V			2	40	20	2	0 μΑ
Ci	V <sub>I</sub> = V <sub>CC</sub> or GND	5 V		2.5	10			1	0 pF

 $<sup>^{\</sup>star}$  On products compliant to MIL-PRF-38535, this parameter is not production tested at  $V_{CC}$  = 0 V.

# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 3.3 V $\pm$ 0.3 V (unless otherwise noted) (see Figure 1)

00	•		, ,	_	-													
PARAMETER	FROM	TO LOAD		TO LOAD		FROM TO LOAD $T_A = 25^{\circ}C$		;	SN54AHC05		SN74AHC05		UNIT					
PARAMETER	(INPUT)	(OUTPUT)	CAPACITANCE	MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT							
tPLZ	А	Y	C 15 pE		2.9**	7.1**	1**	8.5**	1	8.5	nc							
tPZL	A		'	'	'	'	ı	ı	$C_L = 15 \text{ pF}$	CL = 13 pr	1 OL = 15 pr		4**	7.1**	1**	8.5**	1	8.5
tPLZ	^	Y	C: - 50 pF		4.7	10.6	P.10	12	1	12	ns							
tPZL	^		C <sub>L</sub> = 50 pF		5.8	10.6	81	12	1	12	115							

 $<sup>^{\</sup>star\star}$  On products compliant to MIL-PRF-38535, this parameter is not production tested.



# SN54AHC05, SN74AHC05 HEX INVERTERS WITH OPEN-DRAIN OUTPUTS

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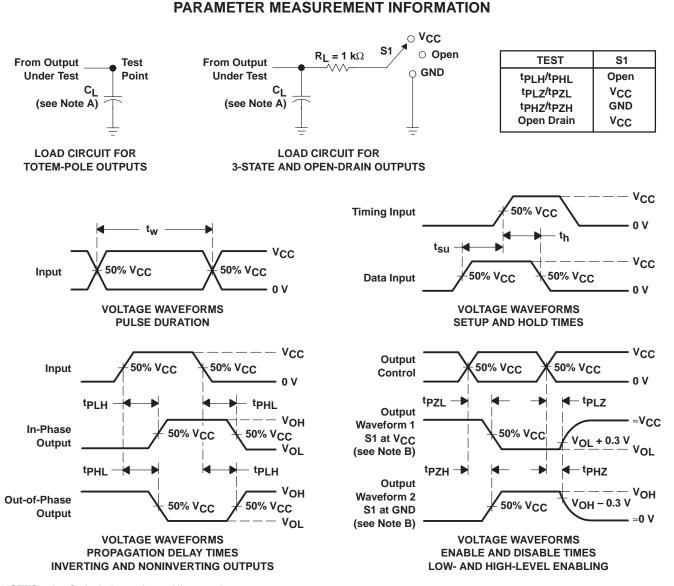
# switching characteristics over recommended operating free-air temperature range, $V_{CC}$ = 5 V $\pm$ 0.5 V (unless otherwise noted) (see Figure 1)

PARAMETER	FROM	то	LOAD CAPACITANCE	LOAD T <sub>A</sub> = 25°0		= 25°C		HC05	SN74AHC05		UNIT								
PARAMETER	(INPUT)	(OUTPUT)		MIN	TYP	MAX	MIN	MAX	MIN	MAX	UNIT								
tPLZ	^	V	C 15 pE		2.2*	5.5*	1*	6.5*	1	6.5	no								
tPZL	A	ı C	1	ı	•	'	•	ı	ι	^   '	$C_L = 15 pF$		2.9*	5.5*	1*	6.5*	1	6.5	ns
tPLZ	А	V	C: 50 pF		3.4	7.5	P10	8.5	1	8.5	20								
t <sub>PZL</sub>		ī	C <sub>L</sub> = 50 pF		4.2	7.5	<b>Q</b> 1	8.5	1	8.5	ns								

<sup>\*</sup> On products compliant to MIL-PRF-38535, this parameter is not production tested.

# operating characteristics, $V_{CC}$ = 5 V, $T_A$ = 25°C

	PARAMETER	TEST CONDITIONS	TYP	UNIT
C <sub>pd</sub>	Power dissipation capacitance	No load, f = 1 MHz	3	pF



NOTES: A.  $C_L$  includes probe and jig capacitance.

- B. Waveform 1 is for an output with internal conditions such that the output is low except when disabled by the output control. Waveform 2 is for an output with internal conditions such that the output is high except when disabled by the output control.
- C. All input pulses are supplied by generators having the following characteristics: PRR  $\leq$  1 MHz,  $Z_O = 50 \Omega$ ,  $t_f \leq 3$  ns.  $t_f \leq 3$  ns.
- D. The outputs are measured one at a time with one input transition per measurement.

Figure 1. Load Circuit and Voltage Waveforms



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